Docket No.: 8733.585.11-US

(PATENT)

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Kyo-Seop CHOO et al.

Confirmation No.: TBA

Application No.: TBA

Group Art Unit: TBA

Filed: April 2, 2004

Examiner: TBA

For: X-RAY DETECTOR AND METHOD OF

FABRICATING THEREFORE

Customer No.: 30827

## **CLAIM FOR PRIORITY**

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Applicant hereby claims priority under 35 U.S.C. 119 based on the following prior foreign application filed in the following foreign country on the date indicated:

Country	Application No.	Date
Korea	2001-12721	March 12, 2001
Korea	2002-00160	January 3, 2002

In support of this claim, Certified copies of the corresponding Convention Application(s) were filed in prior application Serial No. 10/095,105, filed March 12, 2002.

Dated: April 2, 2004

Respectfully submitted,

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